

Mon 05/11/2009-16:11:41.84

TEST 1 - RESET

BHProbe 5.01: Blackhawk USB560m JTAG Emulator

Mon 05/11/2009-16:11:41.98

bin\XDSProbe.exe -v -F BH560USBm.out -p0x0 -r -o log\BHprobe_USB560m.log

-----[Print the reset-command software log-file]-----

This utility has selected an XDS560 class product.
This utility will load the program 'BH560USBm.out'.
This utility will operate on port address '0'.
The controller does use a programmable FPGA.
The old VHDL code has a version number of '1544' (0x0608).
The new VHDL code has a version number of '1544' (0x0608).
The emulator program is named 'BH560USBm.out'.
The emulator program is version '35.24.0.3'.
The controller has a version number of '4' (0x0004).
The controller has an insertion length of '0' (0x0000).
The cable+pod has a version number of '6' (0x0006).
The cable+pod has a capability number of '8' (0x0008).
The local memory has a base address of '0' (0x000000).
The local memory has a word capacity of '32768' (0x008000).
This utility will now attempt to reset the controller.
This utility has successfully reset the controller.

-----[Print the reset-command hardware log-file]-----

The scan-path will be reset by toggling the JTAG TRST signal.
The software is configured to use all Nano-TBC VHDL features.
The controller type is the Nano-TBC VHDL.
The connection type is a 560-class revision-D multi-purpose cable.
The controller will be software reset via its configure register.
The controller will use rising-edge timing on output pins.
The controller may use rising edge timing on input pins.
The controller has a logic ONE on its EMU[0] input pin.
The controller has a logic ONE on its EMU[1] input pin.
The scan-path link-delay has been set to exactly '3' (0x0003).
The support logic has not previously detected a power-loss.

Done.

TEST 2 - SCAN

BHProbe 5.01: Blackhawk USB560m JTAG Emulator

Mon 05/11/2009-16:11:43.56

bin\XDSProbe.exe -v -F BH560USBm.out -p0x0 -i -o log\BHprobe_USB560m.log

-----[Print the controller-open software log-file]-----

This utility has selected an XDS560 class product.
This utility will load the program 'BH560USBm.out'.
This utility will operate on port address '0'.
The controller does use a programmable FPGA.
The emulator program is named 'BH560USBm.out'.
The emulator program is version '35.24.0.3'.
The controller has a version number of '4' (0x0004).
The controller has an insertion length of '0' (0x0000).
The cable+pod has a version number of '6' (0x0006).
The cable+pod has a capability number of '8' (0x0008).
The local memory has a base address of '0' (0x000000).
The local memory has a word capacity of '32768' (0x008000).

-----[Perform the standard path-length test on the JTAG IR and DR]-----

This path-length test uses blocks of 512 32-bit words.

The test for the JTAG IR instruction path-length succeeded.
The JTAG IR instruction path-length is 24 bits.

The test for the JTAG DR bypass path-length succeeded.
The JTAG DR bypass path-length is 4 bits.

-----[Perform the Integrity scan-test on the JTAG IR]-----

This test will use blocks of 512 32-bit words.
This test will be applied just once.

Do a test using 0xFFFFFFFF.
Scan tests: 1, skipped: 0, failed: 0
Do a test using 0x00000000.
Scan tests: 2, skipped: 0, failed: 0
Do a test using 0xFE03E0E2.
Scan tests: 3, skipped: 0, failed: 0
Do a test using 0x01FC1F1D.
Scan tests: 4, skipped: 0, failed: 0
Do a test using 0x5533CCAA.
Scan tests: 5, skipped: 0, failed: 0
Do a test using 0xAACC3355.
Scan tests: 6, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG IR Integrity scan-test has succeeded.

-----[Perform the Integrity scan-test on the JTAG DR]-----

This test will use blocks of 512 32-bit words.
This test will be applied just once.

Do a test using 0xFFFFFFFF.
Scan tests: 1, skipped: 0, failed: 0
Do a test using 0x00000000.
Scan tests: 2, skipped: 0, failed: 0
Do a test using 0xFE03E0E2.
Scan tests: 3, skipped: 0, failed: 0
Do a test using 0x01FC1F1D.
Scan tests: 4, skipped: 0, failed: 0
Do a test using 0x5533CCAA.

Scan tests: 5, skipped: 0, failed: 0
Do a test using 0xAACC3355.
Scan tests: 6, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG DR Integrity scan-test has succeeded.

Done.

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TEST 3 - SCAN2
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    BHPProbe 5.01: Blackhawk USB560m JTAG Emulator
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Mon 05/11/2009-16:11:46.32
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bin\XDSProbe.exe -v -f bin\bh-noscantest.cfg -F BH560USBm.out -p0x0 -i -o log
\BHprobe_USB560m.log

-----[Print the controller-open software log-file]-----

This utility has selected an XDS560 class product.
This utility will load the program 'BH560USBm.out'.
This utility will operate on port address '0'.
The controller does use a programmable FPGA.
The emulator program is named 'BH560USBm.out'.
The emulator program is version '35.24.0.3'.
The controller has a version number of '4' (0x0004).
The controller has an insertion length of '0' (0x0000).
The cable+pod has a version number of '6' (0x0006).
The cable+pod has a capability number of '8' (0x0008).
The local memory has a base address of '0' (0x000000).
The local memory has a word capacity of '32768' (0x008000).

-----[Perform the standard path-length test on the JTAG IR and DR]-----

This path-length test uses blocks of 512 32-bit words.

The test for the JTAG IR instruction path-length succeeded.
The JTAG IR instruction path-length is 24 bits.

The test for the JTAG DR bypass path-length succeeded.
The JTAG DR bypass path-length is 4 bits.

-----[Perform the Integrity scan-test on the JTAG IR]-----

This test will use blocks of 512 32-bit words.
This test will be applied just once.

Do a test using 0xFFFFFFFF.
Scan tests: 1, skipped: 0, failed: 0
Do a test using 0x00000000.
Scan tests: 2, skipped: 0, failed: 0
Do a test using 0xFE03E0E2.
Scan tests: 3, skipped: 0, failed: 0
Do a test using 0x01FC1F1D.
Scan tests: 4, skipped: 0, failed: 0

Do a test using 0x5533CCAA.
Scan tests: 5, skipped: 0, failed: 0
Do a test using 0xAACC3355.
Scan tests: 6, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG IR Integrity scan-test has succeeded.

-----[Perform the Integrity scan-test on the JTAG DR]-----

This test will use blocks of 512 32-bit words.
This test will be applied just once.

Do a test using 0xFFFFFFFF.
Scan tests: 1, skipped: 0, failed: 0
Do a test using 0x00000000.
Scan tests: 2, skipped: 0, failed: 0
Do a test using 0xFE03E0E2.
Scan tests: 3, skipped: 0, failed: 0
Do a test using 0x01FC1F1D.
Scan tests: 4, skipped: 0, failed: 0
Do a test using 0x5533CCAA.
Scan tests: 5, skipped: 0, failed: 0
Do a test using 0xAACC3355.
Scan tests: 6, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG DR Integrity scan-test has succeeded.

Done.

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TEST 4 - DATA
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  BHProbe 5.01: Blackhawk USB560m JTAG Emulator
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Mon 05/11/2009-16:11:48.84
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bin\XDSProbe.exe -v -F BH560USBm.out -p0x0 -g -o log\BHprobe_USB560m.log

-----[Print the controller-open software log-file]-----

This utility has selected an XDS560 class product.
This utility will load the program 'BH560USBm.out'.
This utility will operate on port address '0'.
The controller does use a programmable FPGA.
The emulator program is named 'BH560USBm.out'.
The emulator program is version '35.24.0.3'.
The controller has a version number of '4' (0x0004).
The controller has an insertion length of '0' (0x0000).
The cable+pod has a version number of '6' (0x0006).
The cable+pod has a capability number of '8' (0x0008).
The local memory has a base address of '0' (0x000000).
The local memory has a word capacity of '32768' (0x008000).

-----[Perform the standard path-length test on the JTAG IR and DR]-----

This path-length test uses blocks of 512 32-bit words.

The test for the JTAG IR instruction path-length succeeded.
The JTAG IR instruction path-length is 24 bits.

The test for the JTAG DR bypass path-length succeeded.
The JTAG DR bypass path-length is 4 bits.

-----[Perform the Given Data scan-test on the JTAG IR]-----

This test will use blocks of 512 32-bit words.
This test will be applied just once.
It uses the first 1 of the 10 different test-cases.

Do a test using 0x5533CCAA.
Scan tests: 1, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG IR Given Data scan-test has succeeded.

-----[Perform the Given Data scan-test on the JTAG DR]-----

This test will use blocks of 512 32-bit words.
This test will be applied just once.
It uses the first 1 of the 10 different test-cases.

Do a test using 0x5533CCAA.
Scan tests: 1, skipped: 0, failed: 0
All of the values were scanned correctly.

The JTAG DR Given Data scan-test has succeeded.

Done.